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(54) Title (EN): CRYSTALLINE FORM OF SODIUM HYPOCHLORITE PENTAHYDRATE AND METHOD FOR PRODUCING SAME

(54) Title (FR): FORME CRISTALLINE D'HYPOCHLORITE DE SODIUM PENTAHYDRATÉ ET SON PROCÉDÉ DE PRODUCTION

(54) Title (JA): 次亜塩素酸ナトリウム 5 水和物の結晶体およびその製造方法

(57) Abstract:

(EN): Provided are: a crystalline form of sodium hypochlorite pentahydrate which can be stored for a long period of time, wherein the stability of sodium hypochlorite pentahydrate which is effective as an oxidant or a disinfectant has been improved; and a method for producing the same. The crystalline form of sodium hypochlorite pentahydrate has a peak at a position of an angle of diffraction indicated in Table 1 of claim 1 in a range of $10^{\circ} \leq 2\theta$ (angle of diffraction) $\leq 65^{\circ}$ by powder X-ray diffraction measurements using a $\text{CuK}\alpha$ radiation source.

(FR): L'invention concerne : une forme cristalline d'hypochlorite de sodium pentahydraté qui peut être stockée pendant une longue durée, grâce à laquelle la stabilité de l'hypochlorite de sodium pentahydraté, qui est efficace en tant qu'oxydant ou désinfectant, a été améliorée ; et son procédé de production. La forme cristalline d'hypochlorite de sodium pentahydraté présente un pic à une position d'un angle de diffraction indiqué dans le tableau 1 de la revendication 1 dans une plage de $10^{\circ} \leq 2\theta$ (angle de diffraction) $\leq 65^{\circ}$ par des mesures de diffraction des rayons X sur poudre à l'aide d'une source de rayonnement α du CuK .

(JA): 酸化剤や殺菌剤として有効な次亜塩素酸ナトリウム 5 水和物の常温付近での安定性を向上させた長期保存が可能な次亜塩素酸ナトリウム 5 水和物結晶とその製造方法を提供する。 $\text{CuK}\alpha$ 線源を用いる粉末 X 線回折測定で、 $10^{\circ} \leq 2\theta$ (回折角) $\leq 65^{\circ}$ の範囲において、請求項 1 の表 1 に示す回折角の位置にピークが現れる次亜塩素酸ナトリウム 5 水和物結晶。

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